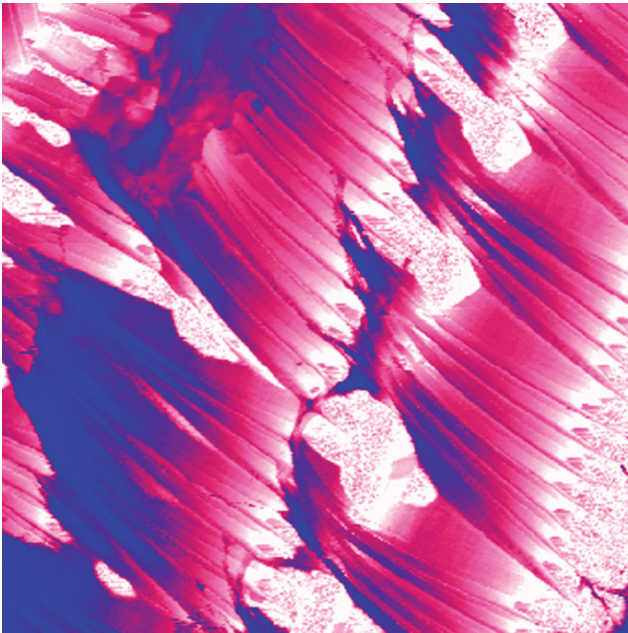
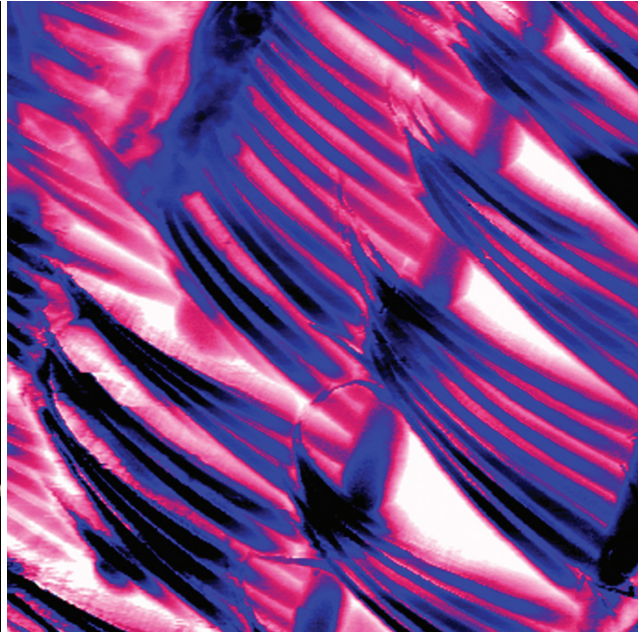
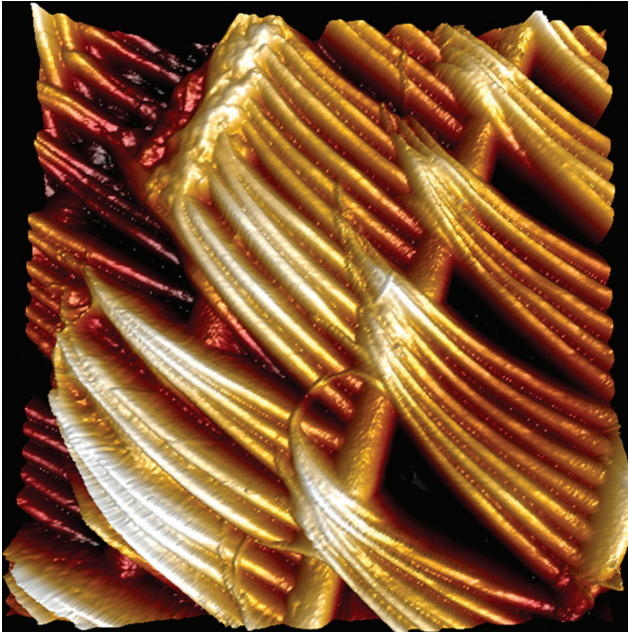


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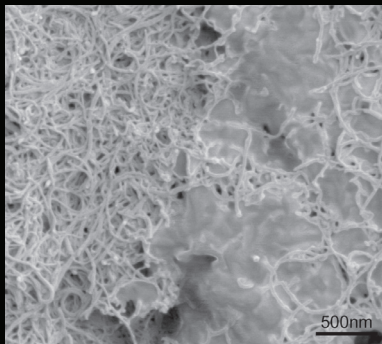


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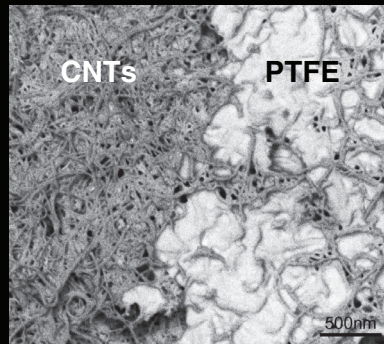
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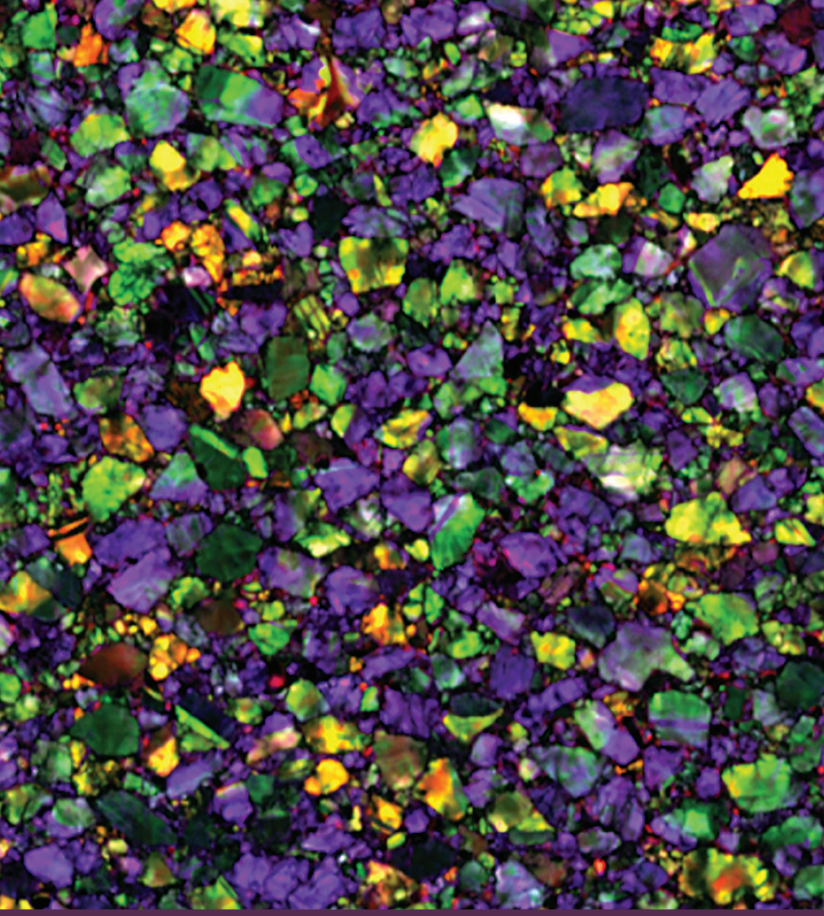
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Sample: Carbon Nanotube (CNT) and Polytetrafluoroethylene (PTFE) composite film (protective film used for fuel cell) Sample Courtesy of Prof. Yoshiyuki SHOW, School of Engineering, Tokai University, Japan

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Image at Top: Cathodoluminescence image of composite SiC-diamond cutting tool; Colin MacRae, CSIRO-Minerals, Clayton, Victoria, Australia

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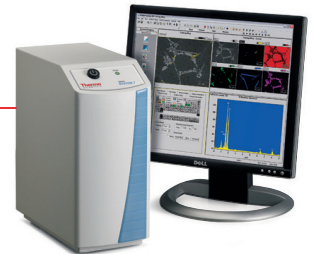
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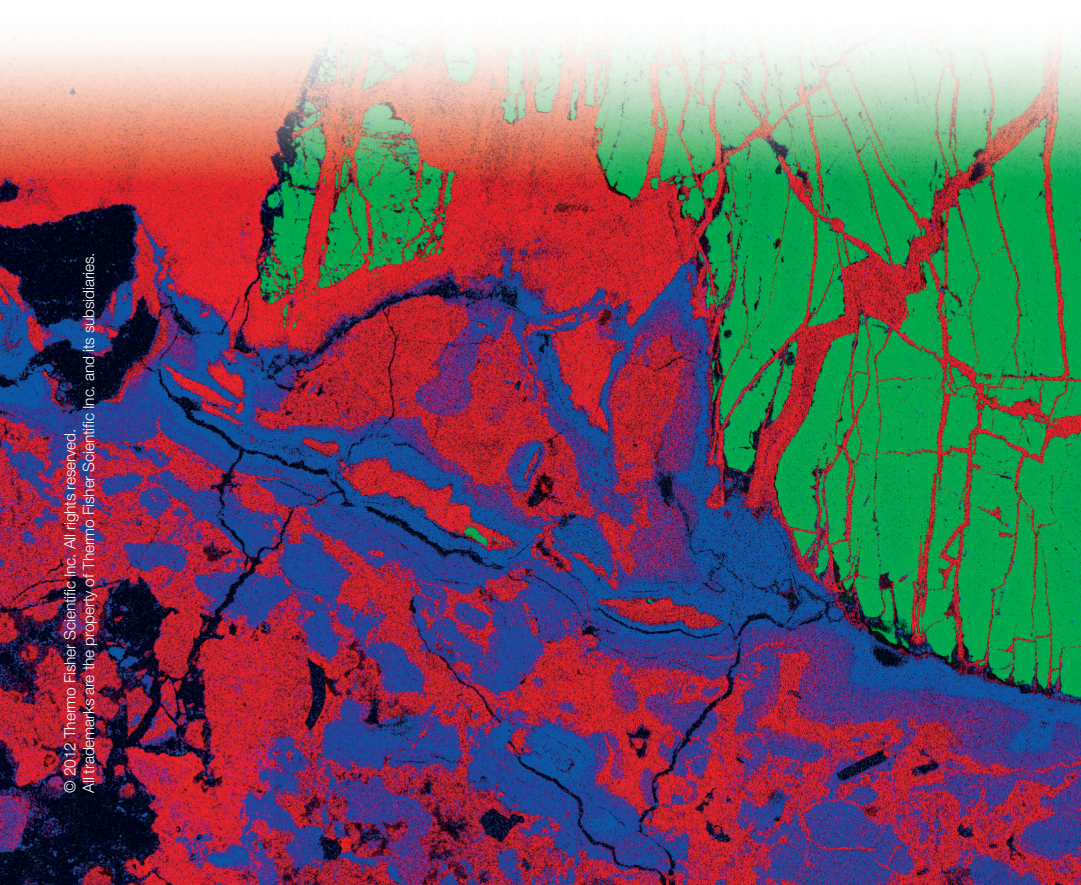
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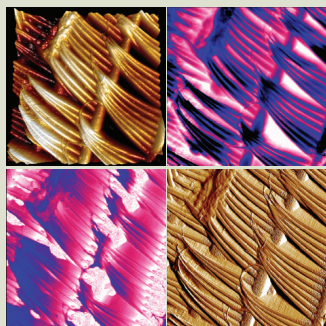
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Atomic force microscopy images of Daphnia captured in Peak Force Tapping mode. Clockwise from top left: topography, Young's modulus, adhesion force, and Peak Force error. Full width = 8 μ m.

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